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High Bit Rate Germanium Single Photon Detectors for 1310 nm

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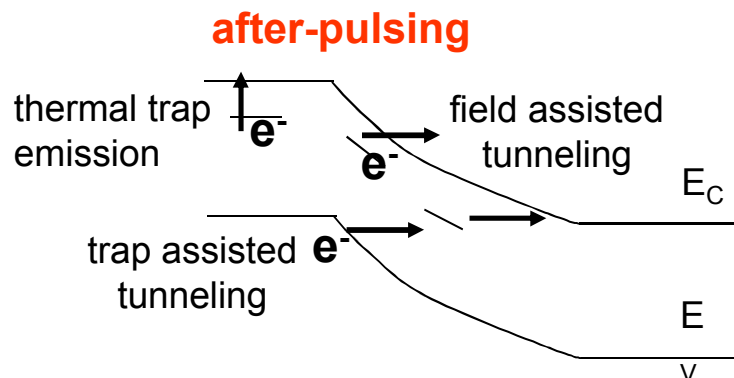
Outline



- **Motivation and applications**
- **Methodology**
- **Ge Avalanche Photodiode (APD) measurements**
- **Summary**

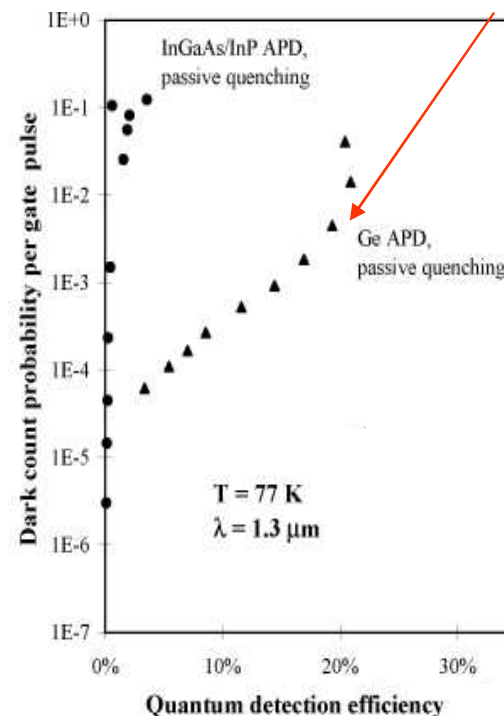
Motivation and Applications

- Potentially enhanced maximum count rate for 1310 nm
 - Ge has over an order of magnitude fewer charge trap density compared to currently available state-of-the-art InGaAs/InP
 - Performance at 1550 nm may be enhanced.



- Single photon detection desired
 - Quantum key distribution (QKD) on dark fiber
 - Eye safe LIDAR imaging
 - Single molecule fluorescence detection
 - Quantum commutation with linear optics

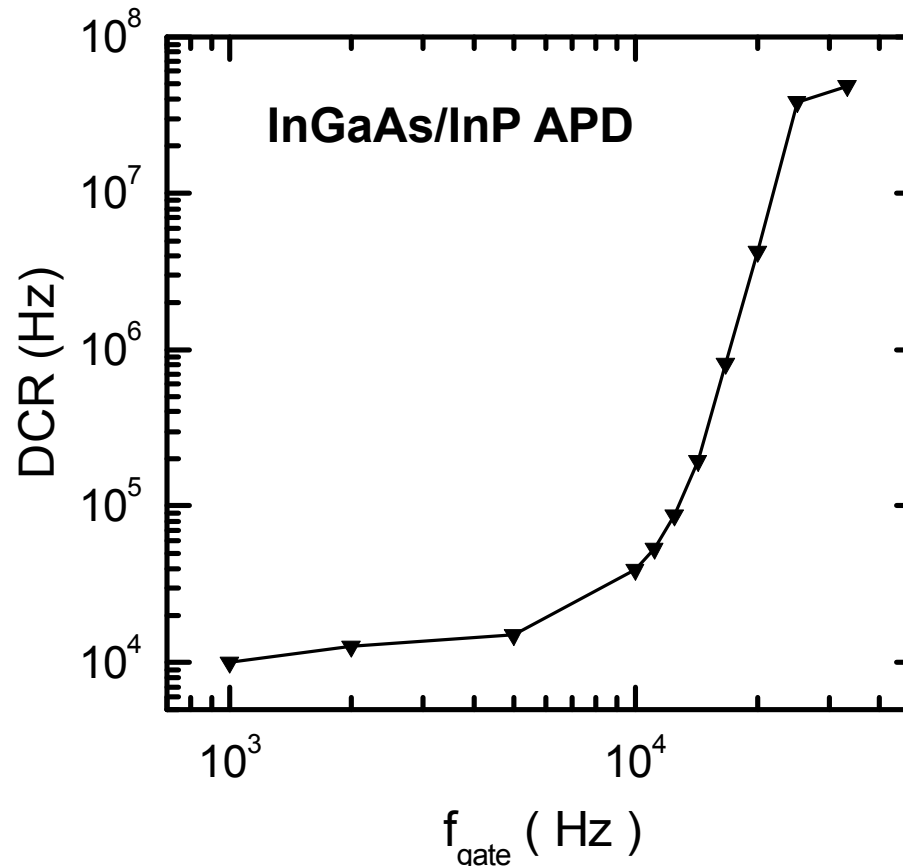
after-pulsing limited for Ge?



Ribordy et al., AO (1998)

After-Pulsing

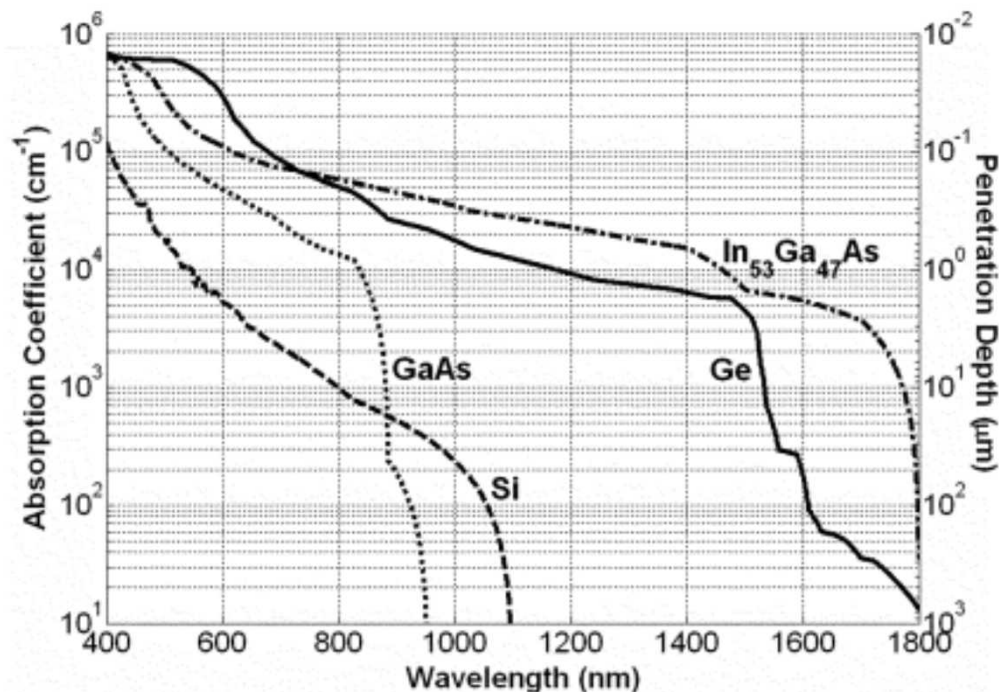
- After-pulsing causes increased dark count rates (DCR)
- After-pulsing is trap related
 - InP has traps which limit the performance at high frequency
 - Ge has fewer traps which motivates this work



*Tosi, Proc. Eur. Solid-State
Dev. Res. 36, 335 (2006)*

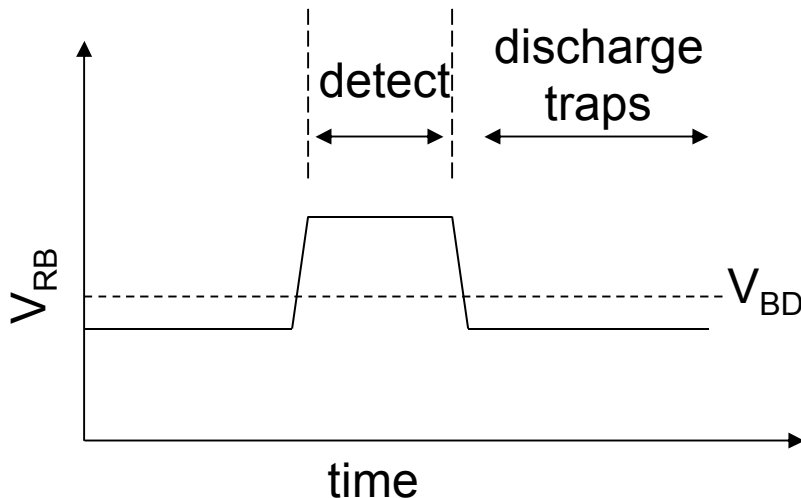
Absorption Coefficients

- Ge has long been ignored for single photon detection in the Near-infrared because of the telecommunications need at 1550 nm.
- QKD may use existing dark fiber at 1310 nm
 - Reopening the usefulness of Ge

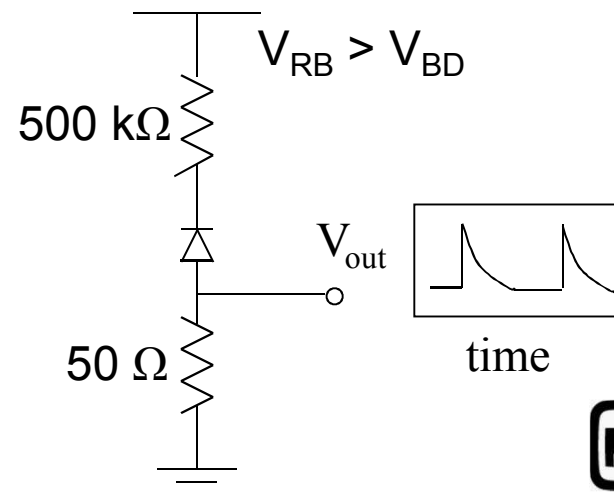


Geiger Mode Operation

- High fields produce avalanche breakdown triggered by single e^-
- GM operates APD above breakdown (V_{BD})
 - Single photon sensitivity
- After-pulsing can be suppressed with gated operation
 - Allows time for trap discharging after avalanche fills them
- Geiger pulse can be passively or actively quenched
- The window of sensitivity is when the junction is at high field during the time before the next thermally generated dark count

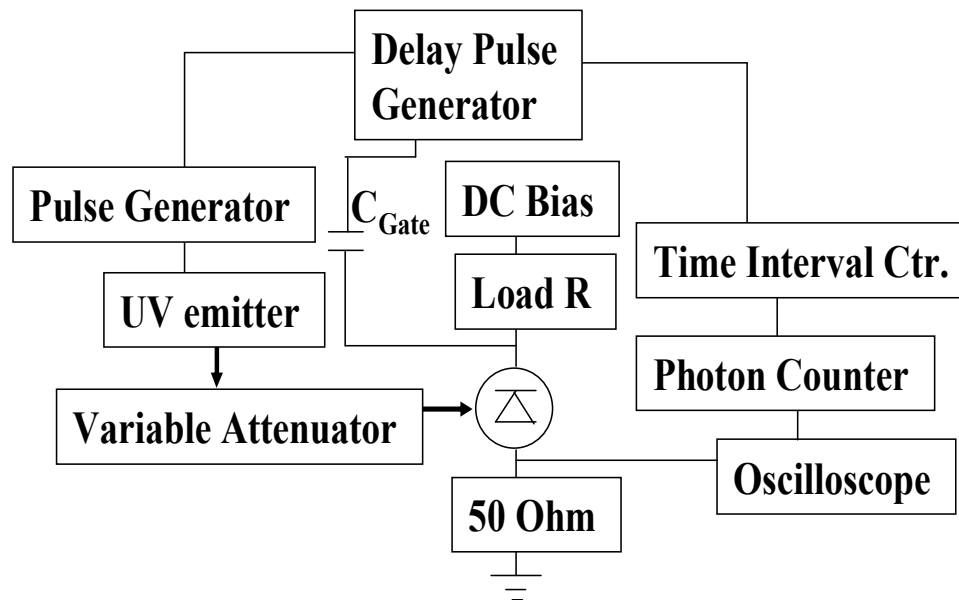


passive quenching configuration



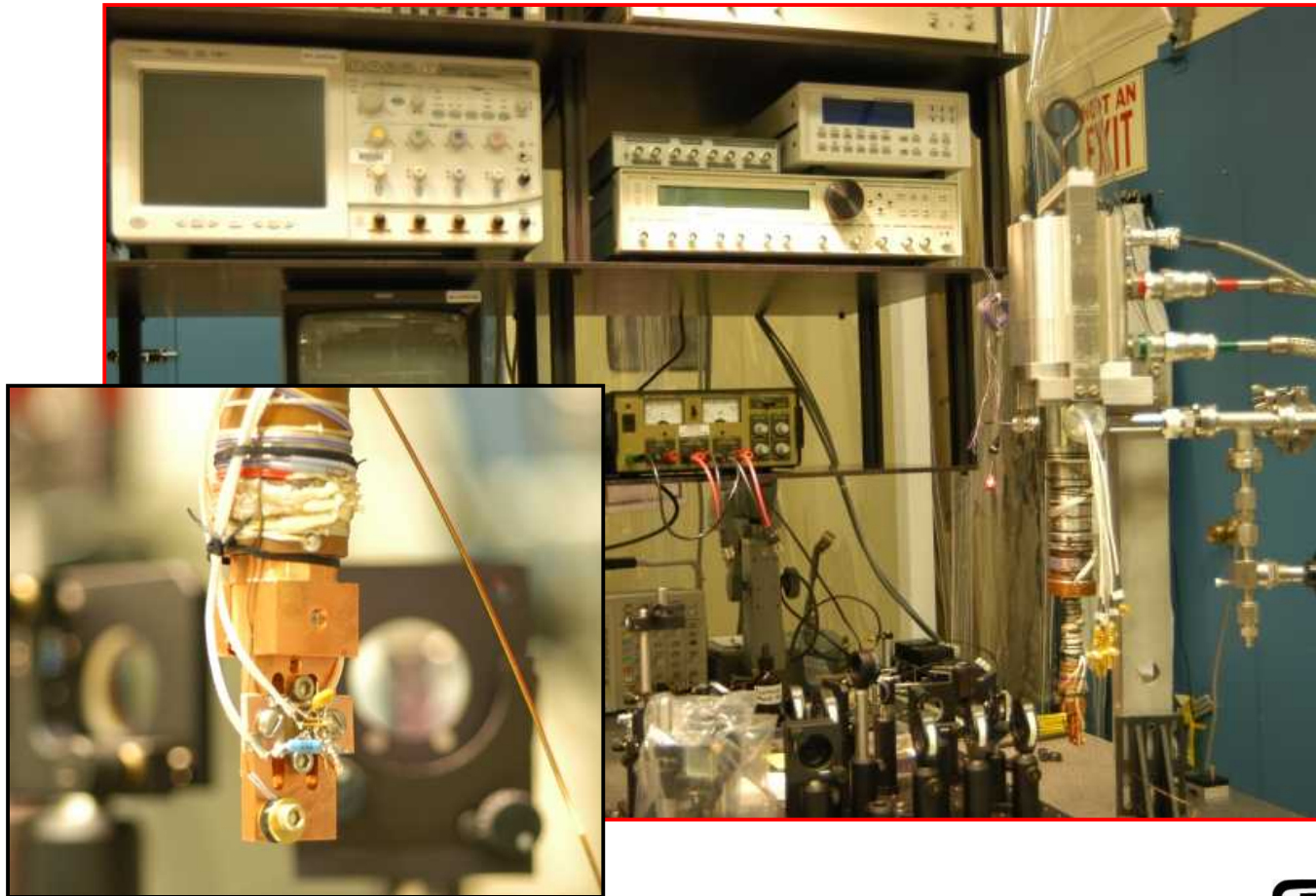
Geiger Mode Setup

- Geiger-mode (GM) operation measurement setup
 - Gating circuit and gate pulse required
 - Gate frequencies typically 1 kHz -100 MHz
 - Gate widths from 4 ns to 10 μ s
 - Detection efficiency (DE) and DCR



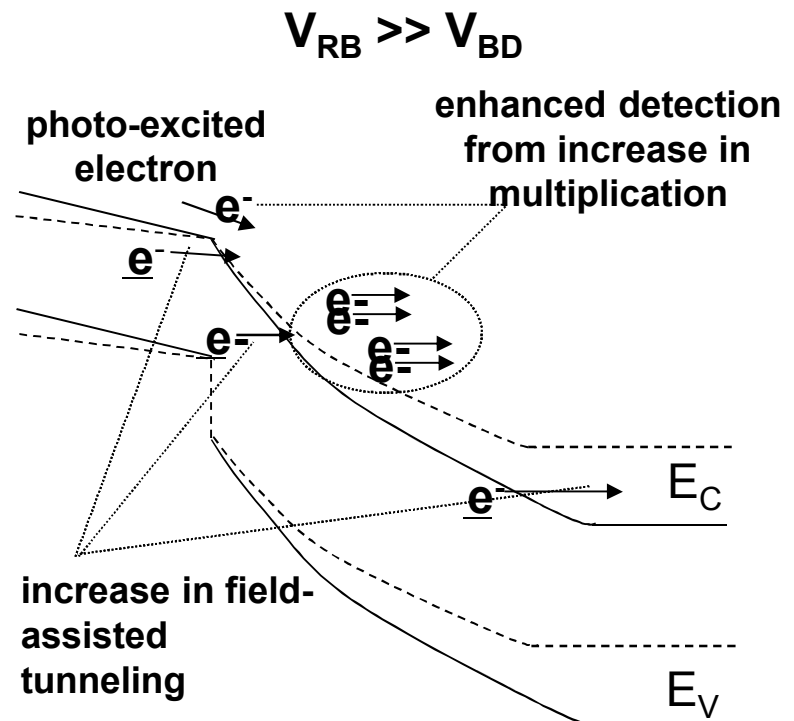
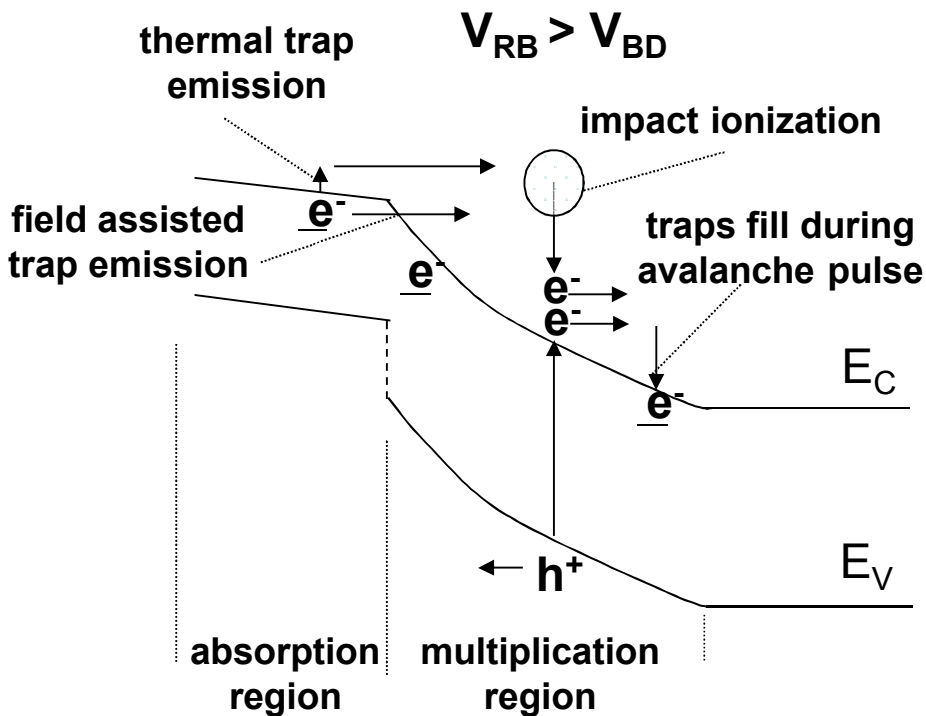
Cryostat Setup

- **Temperature range** 16 K - 350 K
- **Electrical connections** 50-ohm coax. cables



Reverse Bias and DE

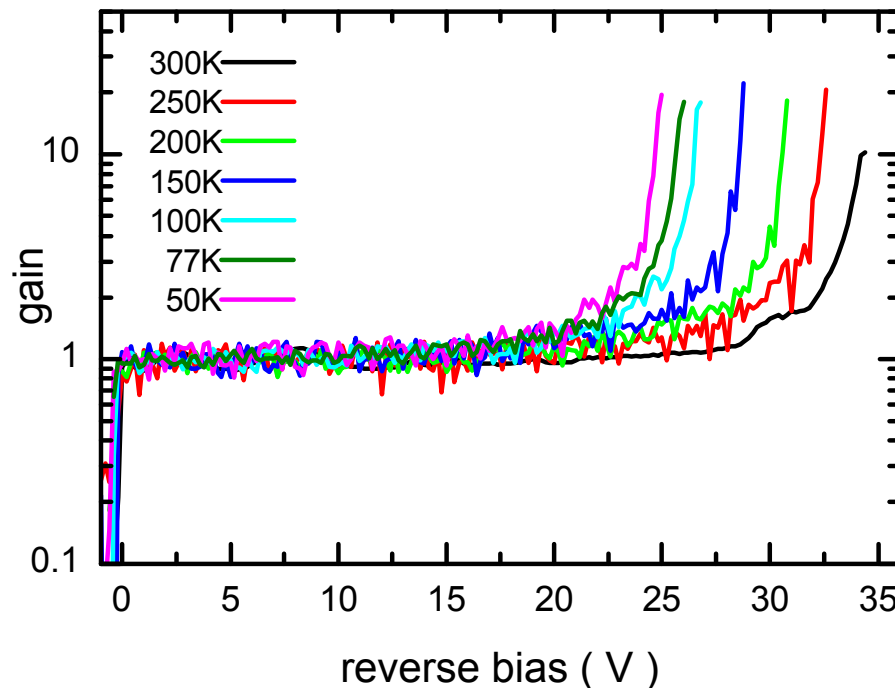
- DE increases with increasing reverse bias (V_{RB})
- Field assisted trap tunneling increases with V_{RB} limiting DE
- DE for NIR devices is typically around 10-30% before dark counts overwhelm signal



Ge APD Multiplication

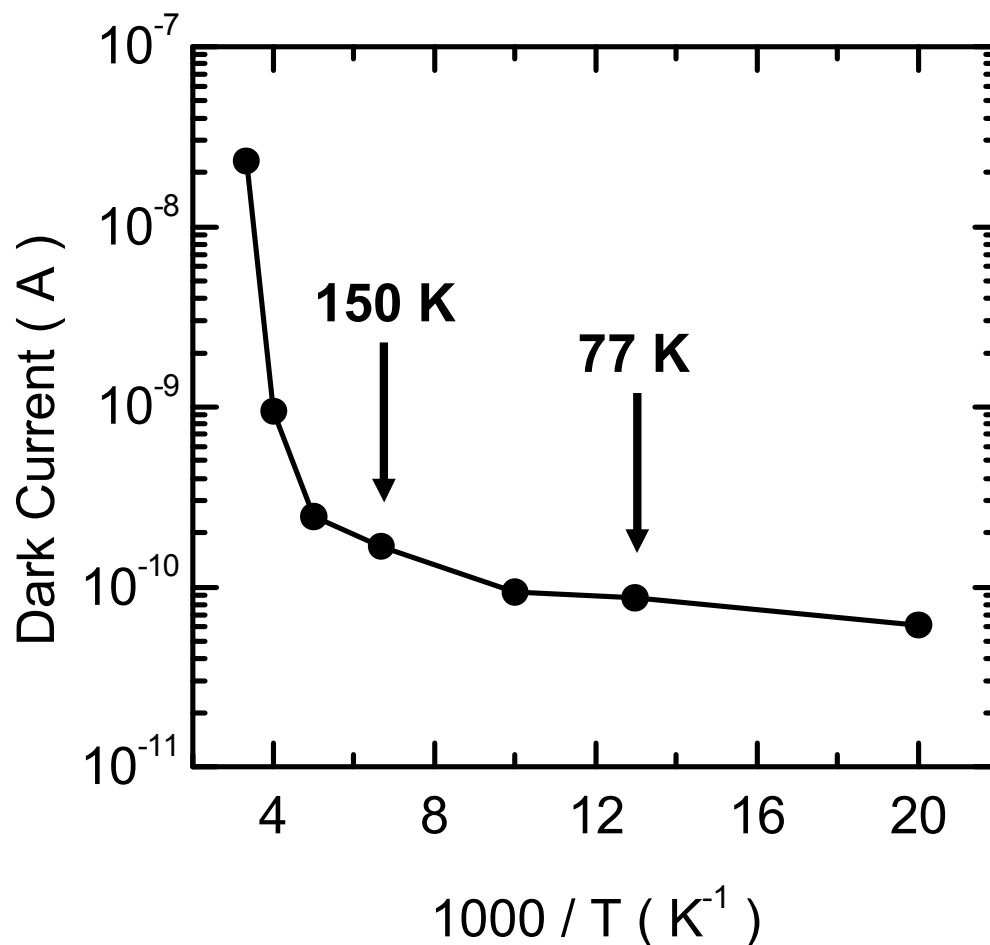
- Avalanche photodiodes (APD) produce internal gain due to high field impact ionization
- Linear mode results in 10-100 x gain
 - Insufficient for single photon detection

10mW optical power incident on Ge APD



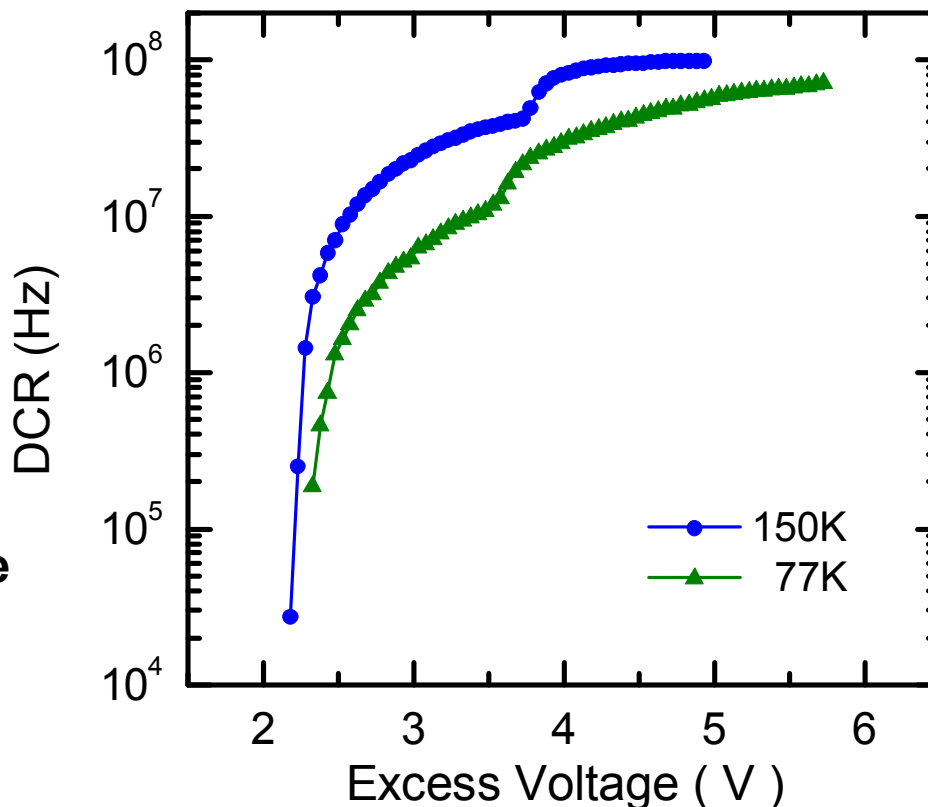
Dark Current

- Arrhenius plot of the dark current in commercial Ge APD
 - Steep decrease in the thermally generated carriers as T^{-1}



Dark Count Rate

- DCR at 1 kHz ensures after-pulsing is not measured
- Weaker than expected T dep. for thermally generated carriers
 - Tunneling mechanism is dominating the DCR below 150K
- Even at this low f_{gate} the DCR for this APD is higher than common for Ge



$$DCR = \frac{N_{\text{counter}}}{T_{\text{on}} f_{\text{gate}}}$$

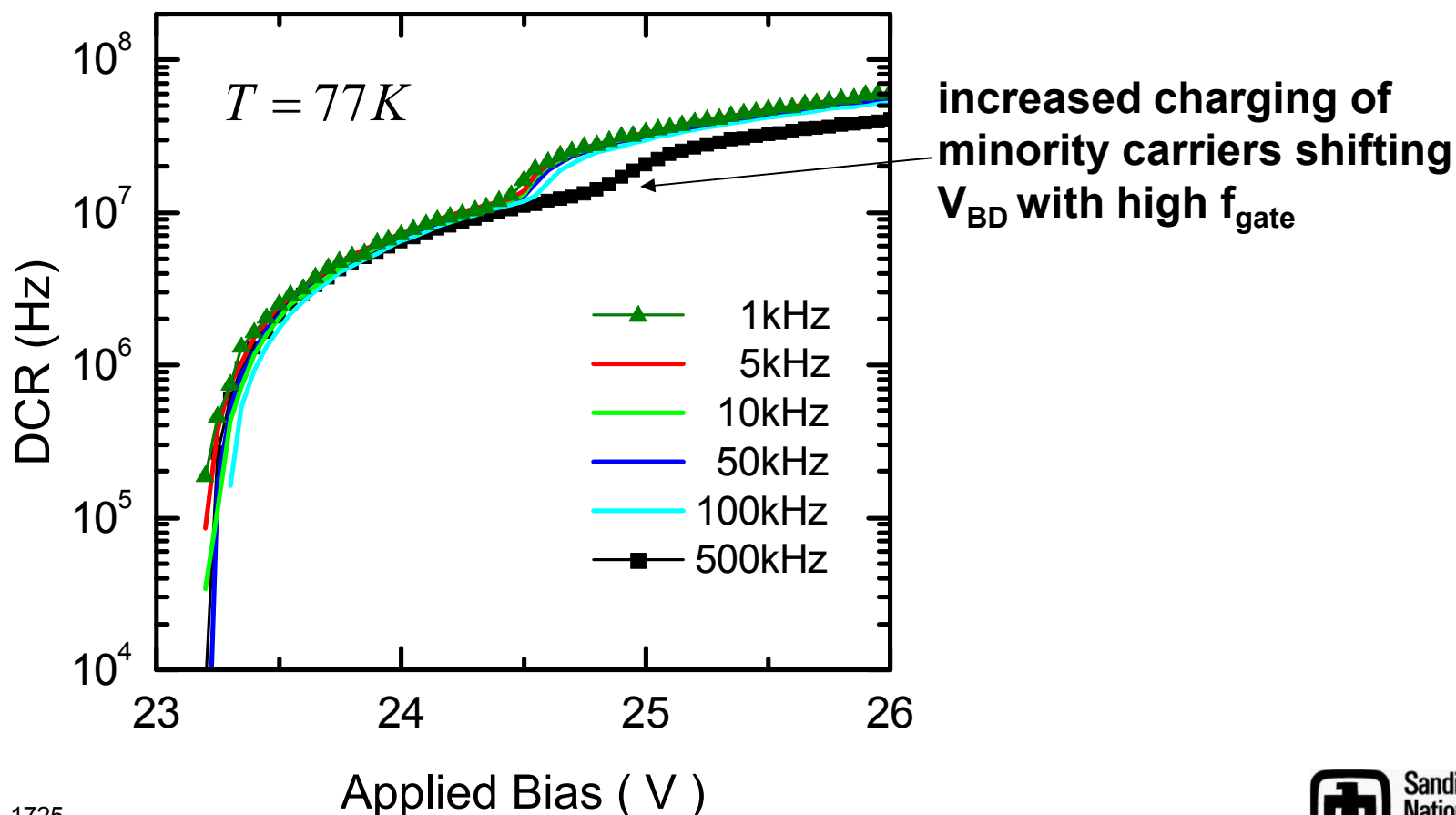
$$f_{\text{gate}} = 1\text{kHz}$$

$$T_{\text{on}} = 20\text{ns}$$

Excess voltage
is VRB - VBD

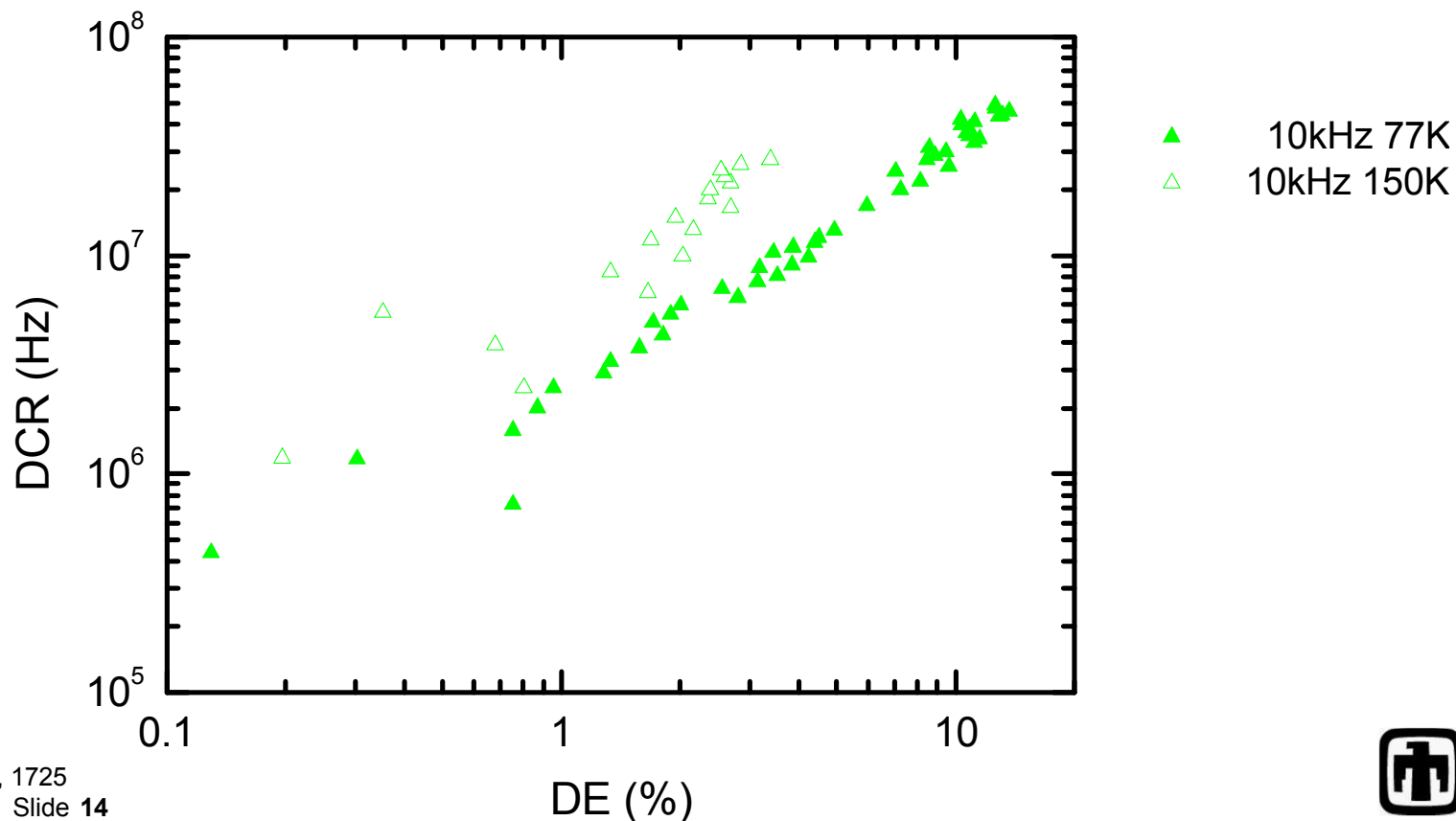
DCR at 77 K

- Increasing f_{gate} to check for after-pulsing
- Tunneling mechanism still dominating the DCR up to 500 kHz



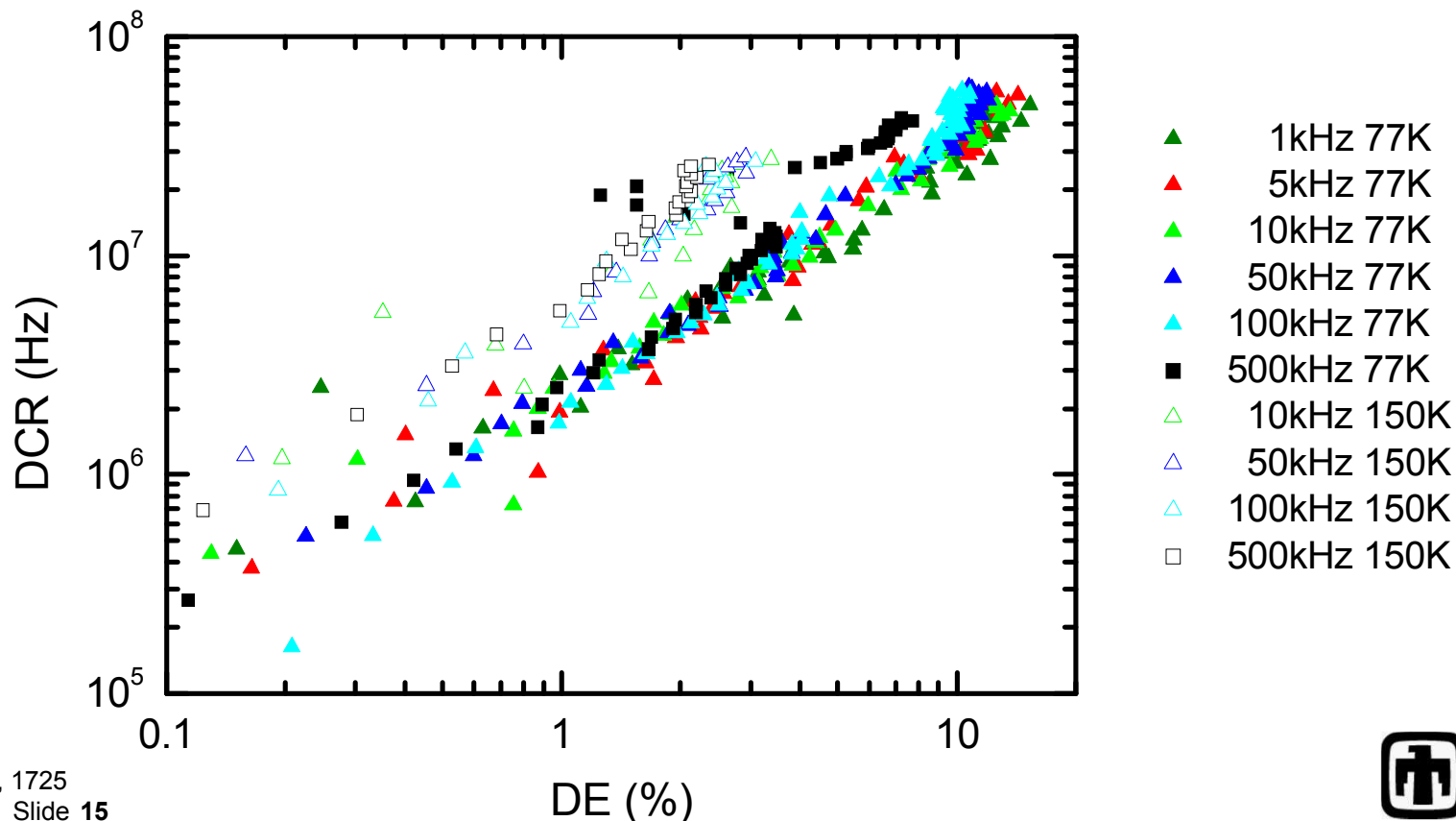
Detection Efficiency

- The Judson Ge APD was not designed for GM
 - Low quantum efficiency (51%) at low T
- DE reaches 15% with 1 photon per gate



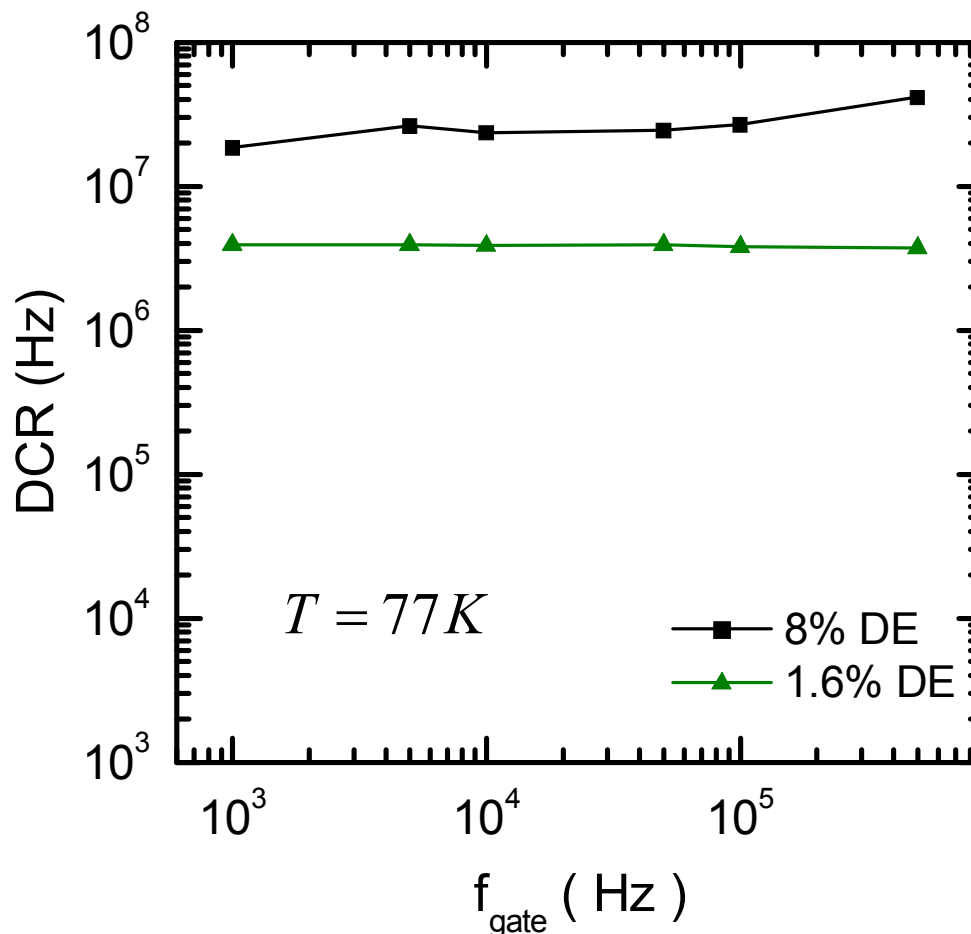
Detection Efficiency

- The Judson Ge APD was not designed for GM
 - Low quantum efficiency (51%) at low T
- DE reaches 15% with 1 photon per gate
- Minimal high frequency penalty



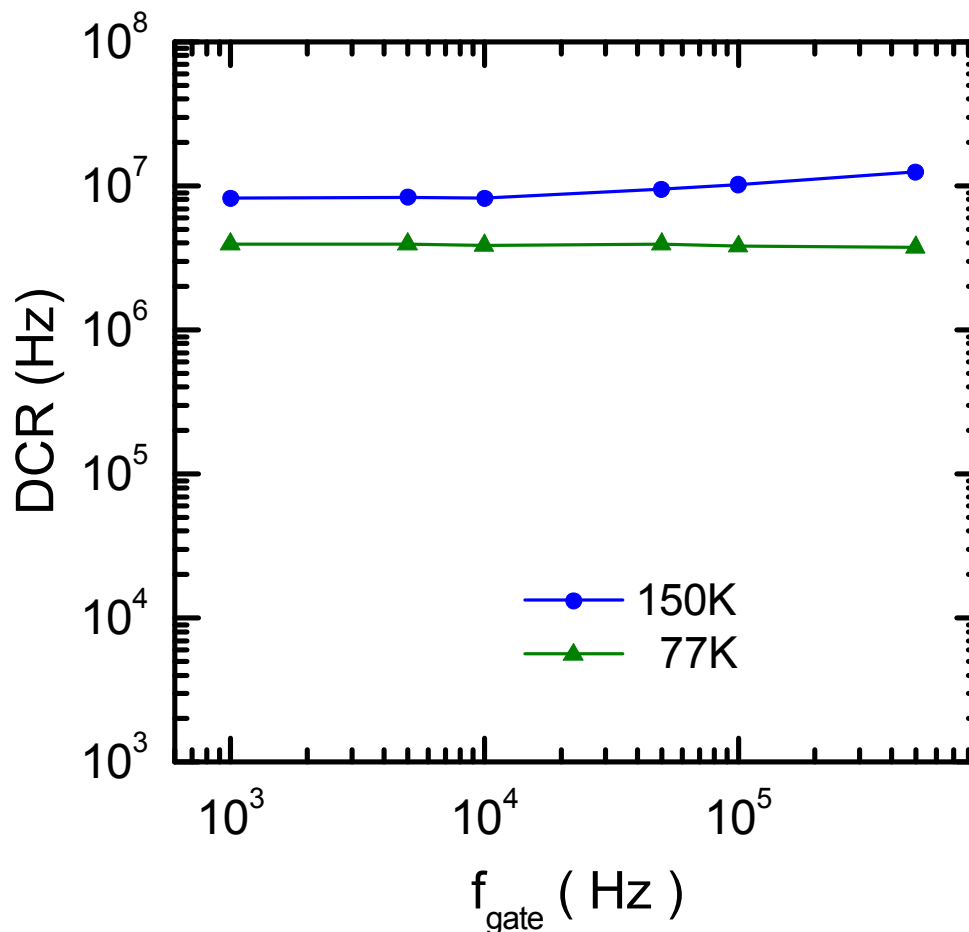
DCR with Fixed DE at 77K

- Ge APD exhibits only a slight increase in DCR at 1.6% DE
- Slight increase in DCR at 8% DE with f_{gate} could be after-pulsing



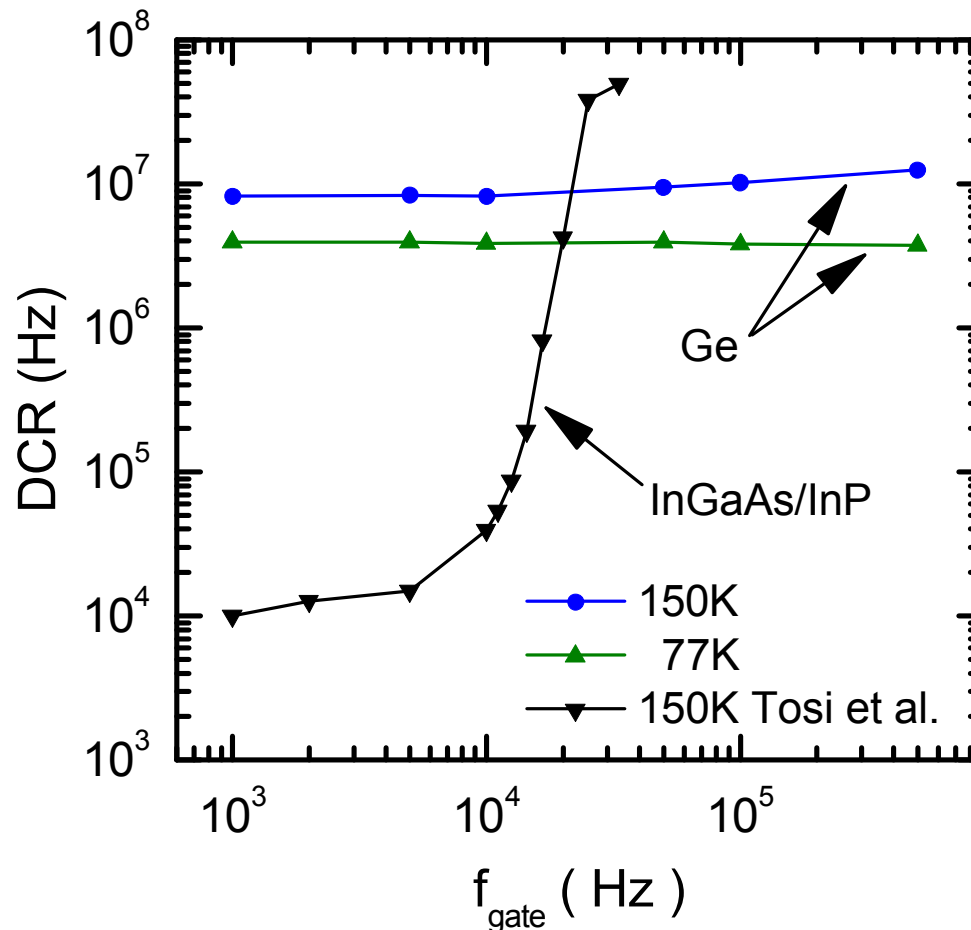
DCR at DE = 1.6%

- Ge APD exhibits only a slight increase in DCR at 1.6% DE
- Increase in DCR at 150K with f_{gate} could be thermally generated after-pulsing



DCR of Ge and InGaAs/InP

- Ge APD exhibits only a slight increase in DCR at 1.6% DE
- DCR in InGaAs/InP APD demonstrate characteristic increase with f_{gate} at an unspecified DE



*Tosi, Proc. Eur. Solid-State
Dev. Res. 36, 335 (2006)*

Summary



- **Commercial Ge APD has been used to demonstrate single photon detection**
- **QKD applications at 1310 nm that can be cooled to ~100-220K range may be best suited for Ge**
 - **Ge heterostructure engineering could significantly raise $T_{\text{operation}}$**
- **DCR while high in this device, showed little increase with f_{gate} up to 500 kHz**
 - **Unlike InGaAs/InP DCR, that increased nearly 4 decades by 20 kHz**
- **Future work includes Ge APD designed for GM and possibly a heterojunction design.**

Acknowledgement



- **Darwin Serkland**
 - **Sandia National Laboratories**
 - **Use of the lab and equipment**

- **Tom Bauwer (check name and spelling)*******
 - **Sandia National Laboratories**
 - **Wiring the cryostat**

Oscilloscope Showing SPAD Operation

